Search Notes			
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Application/Contro	Applicant(s)/Patent u Reexamination	nder
09/754,441	YOSHIHARA ET AL	
Examiner	Art Unit	
Hai V Nguyen	2142	

SEARCHED				
Class	Subclass	Date	Examiner	
709	205, 245	1/20/2007	HN	
84	622	1/20/2007	HN	
		-		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST Search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	1/20/2007	HN
Limited Classified search: 709/205, 245; 84/622 (see search history printout report)	1/20/2007	HN